

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10521173	OKUYAMA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	ANDREW P BAINBRIDGE	3754

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
222	192	3/31/08	APB
250	281-282,286-288,423f,423p,423r,424,435	10/20/2008	APB
378	66,119,210	10/20/2008	APB
361	225-228, 230-235	10/20/2008	APB

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Reviewed all IDS	3/31/08	APB
Angstrom and Nanometer	3/28/08	APB
Soft X Ray	3/28/08	APB
Backwards/ forward searched relevant references	10/20/2008	APB

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/A. P. B./  
Examiner.Art Unit 3754